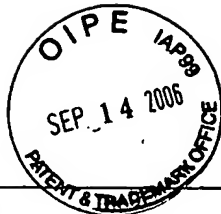


Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. Rule 99(b) Divisional of Application No. 10/263,070 <u>10/748,206</u>	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Satoshi INOUE; Tatsuya SHIMODA			
				FILING DATE December 31, 2003			

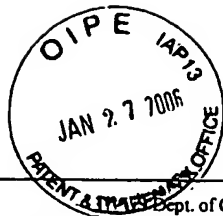
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
RB		5,747,121	05/1998	Okazaki et al.		
		5,767,930	06/1998	Kobayashi et al.		
		5,807,772	09/1998	Takemura		
		5,888,839	03/1999	Ino et al.		
		5,468,521	11/1995	Kanai et al.		
		5,008,218	04/1991	Kawachi et al.		
		5,693,541	12/1997	Yamazaki et al.		
		5,589,962	12/1996	Yamamoto et al.		
		5,527,649	06/1996	Sato et al.		
		5,926,735	07/1999	Yamazaki et al.		
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
RB		JP-A-6-291291	10/1994	JAPAN		
		JP-A-8-288522	11/1996	JAPAN		
		JP-A-61-231714	10/1986	JAPAN		
		JP-A-8-62591	03/1996	JAPAN		
		WO 98/09333	03/1998	WIPO		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
RB		Sameshima, T. "Laser Beam Application to Thin Film Transistors," <u>Applied Surface Science</u> 96-98, (1996), pp. 352-358.				
EXAMINER					DATE CONSIDERED <u>2/3/07</u>	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Date: December 31, 2003

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10/748,206	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Satoshi INOUE et al.			
				FILING DATE December 31, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
AP	1.	Sameshima T., Laser beam application to the thin film transistors, Applied Surface Science, April 2, 1996 Vol. 96-98					
		Pages 352-358					
EXAMINER		<i>Robert Au</i>				DATE CONSIDERED <i>2/3/07</i>	
Examiner:		Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

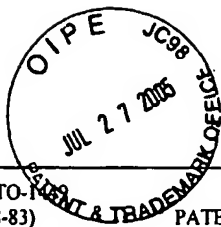
Date: September 14, 2006



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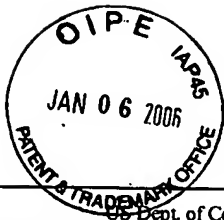
Form PTO-1449 (REV. 1/06)		U.S. Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10748,206	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Satoshi INOUE et al.			
				FILING DATE December 31, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
1A	1.	JP A 07-504782 (corresponds to reference 2)	05/25/1995	Japan			
	2.	WO 93/16491	08/19/1993	WIPO			
1B	3.	JP A 07-294961	11/10/1995	Japan	X	X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER		Richard Ar			DATE CONSIDERED 2/3/05		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: January 27, 2006

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Form PTO-100 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10/748,206	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Satoshi INOUE et al.			
				FILING DATE December 31, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
RB	1	JP07-098460A (w/machine translation)	04/1995	Japan			
	2	JP08-250745A (w/machine translation)	09/1996	Japan			
	3	JP08-262474A (w/machine translation)	10/1996	Japan			
	4	JP08-262475A (w/machine translation)	10/1996	Japan			
	5	JP08-234796A (w/machine translation)	09/1996	Japan			
	6	JP08-278519A (w/machine translation)	10/1996	Japan			
	7	JP05-218365A (w/machine translation)	08/1993	Japan			
	8	JP08-240814A (w/machine translation)	09/1996	Japan			
	9	JP06-202160A (w/machine translation)	07/1994	Japan			
			JP63-101830A (w/Abstract)	05/1988	Japan		
AB		JP63-101832A (w/Abstract)	05/1988	Japan			
		JP04-170520A (w/Abstract)	06/1992	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER <i>Richard A. K.</i>				DATE CONSIDERED <i>2/3/07</i>			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: July 27, 2005

Sheet 1 of 1Form PTO-1449
(REV. 8-83)U.S. Dept. of Commerce
PATENT & TRADEMARK OFFICEATTY DOCKET NO.
040852.98APPLICATION NO.
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INFORMATION DISCLOSURE STATEMENT

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December 31, 2003GROUP
2812

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
AC	1	WO 92/12453	07/23/1992	WIPO		
	2	JP-A-06-504139	05/12/1994	JAPAN		
	3	JP-A-06-219052 (w/English- language Abstract & Translation)	08/09/1994	JAPAN		
AB	4	JP-A-06-118441 (w/English- language Abstract & Translation)	04/28/1994	JAPAN		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

2/3/07

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Date: January 6, 2006